







SN54HCT273, SN74HCT273 SCLS068G - NOVEMBER 1988 - REVISED JULY 2022

# SNx4HCT273 Octal D-Type Flip-Flops With Clear

### 1 Features

- Operating voltage range of 4.5 V to 5.5 V
- Outputs can drive up to 10 LSTTL loads
- Low power consumption, 80 µA maximum I<sub>CC</sub>
- Typical  $t_{pd}$  = 12 ns
- ±4 mA output drive at 5 V
- Low input current of 1 µA maximum
- Inputs are TTL-voltage compatible
- Contain eight D-type flip-flops
- Direct clear input

### 2 Applications

- Buffer or storage registers
- Shift registers
- Pattern generators

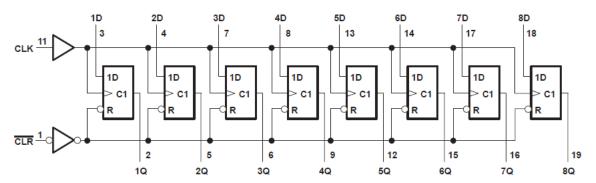
### 3 Description

These devices are positive-edge-triggered D-type flipflops with a common enable input. The 'HCT273 devices are similar to the 'HCT377 devices, but feature a common clear enable (CLR) input instead of a latched clock.

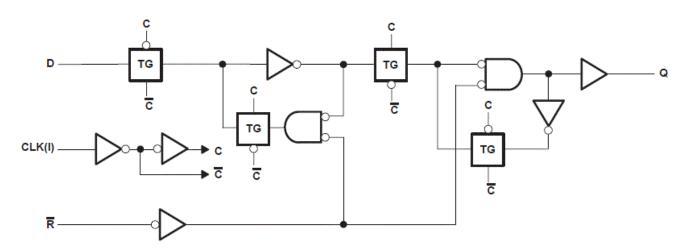
### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)
SN74HCT273DW	SOIC (20)	12.80 mm × 7.50 mm
SN74HCT273DB	SSOP (20)	7.20 mm × 5.30 mm
SN74HCT273N	PDIP (20)	25.40 mm × 6.35 mm
SN74HCT273NS	SO (20)	15.00 mm × 5.30 mm
SN74HCT273PW	TSSOP (20)	6.50 mm × 4.40 mm

For all available packages, see the orderable addendum at the end of the data sheet.



Logic Diagram, (postive logic)



Logic Diagram, Each Flip Flop (positive logic)



### **Table of Contents**

1 Features1	8 Detailed Description
2 Applications1	8.1 Overview
3 Description1	8.2 Functional Block Diagram
4 Revision History2	8.3 Device Functional Modes
5 Pin Configuration and Functions3	9 Power Supply Recommendations
6 Specifications4	10 Layout
6.1 Absolute Maximum Ratings4	10.1 Layout Guidelines
6.2 Recommended Operating Conditions <sup>(1)</sup>	11 Device and Documentation Support1
6.3 Thermal Information4	11.1 Receiving Notification of Documentation Updates 10
6.4 Electrical Characteristics5	11.2 Support Resources10
6.5 Timing Requirements5	11.3 Trademarks10
6.6 Switching Characteristics6	11.4 Electrostatic Discharge Caution10
6.7 Switching Characteristics6	11.5 Glossary10
6.8 Operating Characteristics6	12 Mechanical, Packaging, and Orderable
7 Parameter Measurement Information7	Information10
4 Revision History	

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

### Changes from Revision F (February 2022) to Revision G (July 2022)

### **Page**

Junction-to-ambient thermal resistance values increased. DW was 58 is now 109.1, DB was 70 is now 122.7, N was 69 is now 84.6, NS was 60 is now 113.4, PW was 83 is now 131.8......4

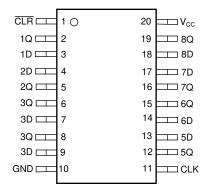
### Changes from Revision E (August 2003) to Revision F (February 2022)

### **Page**

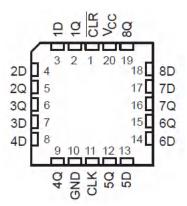
Updated the numbering, formatting, tables, figures, and cross-references throughout the doucment to reflect 



# **5 Pin Configuration and Functions**



DB, DW, N, NS, or PW package 20-Pin SSOP, SOIC, PDIP, SO, or TSSOP (Top View)



FK package 20-Pin LCCC (Top View)



### **6 Specifications**

### **6.1 Absolute Maximum Ratings**

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range		-0.5	7	V
I <sub>IK</sub>	Input clamp current <sup>(2)</sup>	$V_I < 0$ or $V_I > V_{CC}$		±20	mA
I <sub>OK</sub>	Output clamp current <sup>(2)</sup>	$V_O < 0$ or $V_O > V_{CC}$		±20	mA
Io	Continuous output current	$V_O = 0$ to $V_{CC}$		±25	mA
	Continuous current through V <sub>CC</sub> or GN	ID		±50	mA
T <sub>J</sub>	Junction temperature			150	°C
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### **6.2 Recommended Operating Conditions**(1)

			SN5	4HCT273	3(2)	SN	74HCT27	73	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
V <sub>CC</sub>	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
V <sub>IH</sub>	High-level input voltage	V <sub>CC</sub> = 4.5 V to 5.5 V	2			2			V
V <sub>IL</sub>	Low-level input voltage	V <sub>CC</sub> = 4.5 V to 5.5 V			0.8			8.0	V
VI	Input voltage		0		V <sub>CC</sub>	0		V <sub>CC</sub>	V
Vo	Output voltage		0		V <sub>CC</sub>	0		V <sub>CC</sub>	V
Δt/Δν	Input transition rise or fall ra			500			500	ns/V	
T <sub>A</sub>	Operating free-air temperate	ıre	-55		125	-40		85	°C

<sup>(1)</sup> All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

### 6.3 Thermal Information

		DW (SOIC)	DB (SSOP)	N (PDIP)	NS (SO)	PW (TSSOP)	
THERMAL	_ METRIC	20 PINS	20 PINS	20 PINS	20 PINS	20 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance <sup>(1)</sup>	109.1	122.7	84.6	113.4	131.8	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	76	81.6	72.5	78.6	72.2	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	77.6	77.5	65.3	78.4	82.8	°C/W
ΨЈТ	Junction-to-top characterization parameter	51.5	46.1	55.3	47.1	21.5	°C/W
ΨЈВ	Junction-to-board characterization parameter	77.1	77.1	65.2	78.1	82.4	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	N/A	N/A	N/A	N/A	N/A	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.

Submit Document Feedback

<sup>(2)</sup> The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>(2)</sup> Product Preview

### **6.4 Electrical Characteristics**

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST C	V <sub>cc</sub>	Т	<sub>A</sub> = 25°C		SN54HC	T273 <sup>(1)</sup>	SN74HC	CT273	UNIT	
PARAMETER	1231 0	TEST CONDITIONS			TYP	MAX	MIN	MAX	MIN	MAX	J. C. T. C.
V <sub>OH</sub>	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		4.4		V
∨он	VI - VIH OI VIL	$I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.30		3.7		3.84		v
V	V <sub>I</sub> = V <sub>IH</sub> or V <sub>II</sub>	I <sub>OL</sub> = 20 μA	4.5 V		0.001	0.1		0.1		0.1	V
V <sub>OL</sub>	VI - VIH OI VIL	I <sub>OL</sub> = 4 mA	4.5 V		0.17	0.26		0.4		0.33	V
I <sub>I</sub>	$V_I = V_{CC}$ or 0		5.5 V		±0.1	±100		±1000		±1000	nA
I <sub>CC</sub>	$V_I = V_{CC}$ or 0,	I <sub>O</sub> = 0	5.5 V			8		160		80	μA
ΔI <sub>CC</sub> (2)	One input at 0.5 Other inputs at 0	,	5.5 V		1.4	2.4		3		2.9	mA
C <sub>i</sub>			4.5 V to 5 V		3	10		10		10	pF

<sup>(1)</sup> Product Preview

### 6.5 Timing Requirements

over recommended operating free-air temperature range (unless otherwise noted)

	PARAME	TED	V	T <sub>A</sub> = 2	5°C	SN54HC	Γ273 <sup>(1)</sup>	SN74HC	T273	UNIT
	PARAIVII	IIEK	V <sub>cc</sub>	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
f <sub>clock</sub>	Clock frequency	4.5 V		25		16		20	MHz	
clock	Clock frequency		5.5 V		28		19		23	IVII IZ
		CLK high or low	4.5 V	20		30		25		
	Pulse duration	CLK High of low	5.5 V	18		25		22		
t <sub>w</sub>	w Pulse duration	CLR low	4.5 V	16		24		20		ns
		CLR IOW	5.5 V	14		20		17		
		Data	4.5 V	20		30		25		
	Satura timo hafara CLKA	Dala	5.5 V	17		25		21		no
Lsu	t <sub>su</sub> Setup time before CLK↑	CLR inactive	4.5 V	20		30		25		ns
		CLR mactive	5.5 V	17		25		21		
	Hald time and the office OLIVA		4.5 V	0		0		0		no
t <sub>h</sub>	Hold time, data after CLK↑	5.5 V	0		0		0		ns	

(1) Product Preview

<sup>(2)</sup> This is the increase in supply current for each input that is at one of the specified TTL voltage levels, rather than 0 V or V<sub>CC</sub>.



### **6.6 Switching Characteristics**

over recommended operating free-air temperature range,  $V_{CC}$  = 5 V ± 0.5 V (unless otherwise noted) (see Parameter Measurement Information)

					SNS	4HCT27	<b>73</b> <sup>(1)</sup>		
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>cc</sub>	T	T <sub>A</sub> = 25°C		MIN MAX		UNIT
	( ,	(301131)		MIN	TYP	MAX	IVIIIN	IVIAA	
f			4.5 V	25	31		16		MHz
f <sub>max</sub>			5.5 V	28	37		19		IVII IZ
+	CLR	Any	4.5 V		15	34		50	no
t <sub>pd</sub>	CLR	Any	5.5 V		12	29		42	ns
	CLR	Any	4.5 V		17	15		50	no
t <sub>PHL</sub>	CLR	Any	5.5 V		15	34		42	ns
4		Any	4.5 V		8	18		22	no
t <sub>t</sub>		Any	5.5 V		7	19		21	ns

<sup>(1)</sup> Product Preview

### **6.7 Switching Characteristics**

over recommended operating free-air temperature range,  $V_{CC}$  = 5 V  $\pm$  0.5 V (unless otherwise noted) (see Parameter Measurement Information)

					SN	74HCT27	3		
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>cc</sub>	T <sub>A</sub> = 25°C			MINI MAY		UNIT
	( 5.7)	(331.31)		MIN	TYP	MAX	MIN	MAX	
f			4.5 V	25	31		20		MHz
f <sub>max</sub>			5.5 V	28	37		23		IVITIZ
4	CLR	Any	4.5 V		15	34		42	ns
t <sub>pd</sub>	CLK		5.5 V		12	29		36	115
+	CLR	Any	4.5 V		17	34		42	no
t <sub>PHL</sub>	CLK	Any	5.5 V		15	29		36	ns
+		Any	4.5 V		8	15		19	no
t <sub>t</sub>		Any	5.5 V		7	14		17	ns

### 6.8 Operating Characteristics

 $V_{CC} = 5 \text{ V}, T_{\Delta} = 25^{\circ}\text{C}$ 

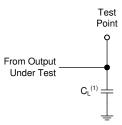
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance	No load	30	pF

### 7 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O$  = 50  $\Omega$ ,  $t_t$  < 6 ns.

For clock inputs,  $f_{\text{max}}$  is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.



(1) C<sub>L</sub> includes probe and test-fixture capacitance.

Figure 7-1. Load Circuit for Push-Pull Outputs

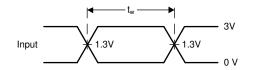


Figure 7-2. Voltage Waveforms, TTL-Compatible CMOS Inputs Pulse Duration

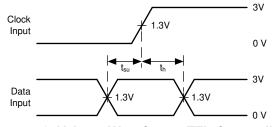
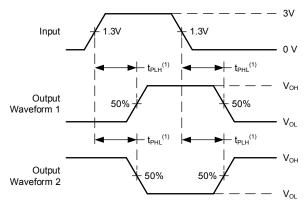


Figure 7-3. Voltage Waveforms, TTL-Compatible CMOS Inputs Setup and Hold Times



(1) The greater between  $t_{\text{PLH}}$  and  $t_{\text{PHL}}$  is the same as  $t_{\text{pd}}$ .

Figure 7-4. Voltage Waveforms, Propagation Delays for TTL-Compatible Inputs

### **8 Detailed Description**

### 8.1 Overview

These devices are positive-edge-triggered D-type flip-flops with a common enable input. The 'HCT273 devices are similar to the 'HCT377 devices, but feature a common clear enable (CLR) input instead of a latched clock.

Information at the data (D) inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock (CLK) pulse. Clock triggering occurs at a particular voltage level and is not directly related to the positive-going pulse. When CLK is at either the high or low level, the D input has no effect at the output. The circuits are designed to prevent false clocking by transitions at  $\overline{\text{CLR}}$ .

### 8.2 Functional Block Diagram

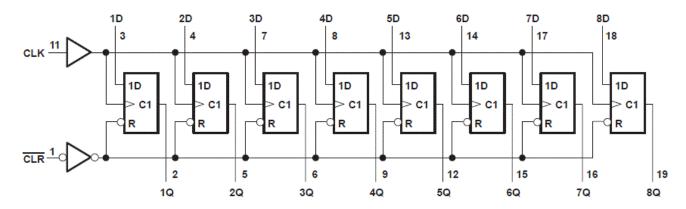


Figure 8-1. Logic Diagram (positive logic)

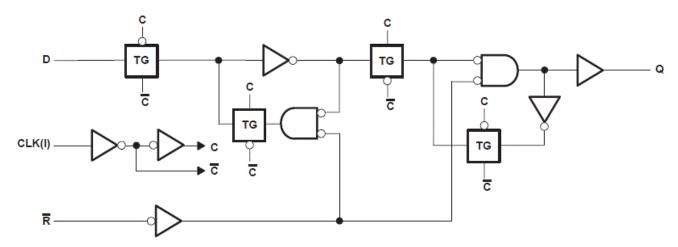


Figure 8-2. Logic Diagram, each flip-flop (potitive logic)

### 8.3 Device Functional Modes

Table 8-1. Function Table (Each Flip-Flop)

	INPUTS		OUTPUT		
CLR	CLK	D	Q		
L	Х	Х	L		
Н	1	Н	Н		
Н	1	L	L		
Н	L	Х	$Q_0$		



### 9 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- $\mu$ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- $\mu$ F and 1- $\mu$ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

### 10 Layout

### 10.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or  $V_{CC}$ , whichever makes more sense for the logic function or is more convenient.



### 11 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

### 11.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 11.2 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

### 11.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

### 11.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### 11.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

### 12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Submit Document Feedback

Copyright © 2022 Texas Instruments Incorporated

www.ti.com 11-May-2023

### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN74HCT273DBR	ACTIVE	SSOP	DB	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HT273	Samples
SN74HCT273DWR	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HCT273	Samples
SN74HCT273DWRG4	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HCT273	Samples
SN74HCT273N	ACTIVE	PDIP	N	20	20	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 85	SN74HCT273N	Samples
SN74HCT273NSR	ACTIVE	SO	NS	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HCT273	Samples
SN74HCT273PWR	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HT273	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.



## PACKAGE OPTION ADDENDUM

www.ti.com 11-May-2023

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.



www.ti.com 12-May-2023

### TAPE AND REEL INFORMATION



# TAPE DIMENSIONS + K0 - P1 - B0 W Cavity - A0 -

A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HCT273DBR	SSOP	DB	20	2000	330.0	16.4	8.2	7.5	2.5	12.0	16.0	Q1
SN74HCT273DBR	SSOP	DB	20	2000	330.0	16.4	8.2	7.5	2.5	12.0	16.0	Q1
SN74HCT273DWR	SOIC	DW	20	2000	330.0	24.4	10.9	13.3	2.7	12.0	24.0	Q1
SN74HCT273NSR	so	NS	20	2000	330.0	24.4	8.4	13.0	2.5	12.0	24.0	Q1
SN74HCT273NSR	so	NS	20	2000	330.0	24.4	8.4	13.0	2.5	12.0	24.0	Q1
SN74HCT273PWR	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1



www.ti.com 12-May-2023



### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74HCT273DBR	SSOP	DB	20	2000	356.0	356.0	35.0
SN74HCT273DBR	SSOP	DB	20	2000	356.0	356.0	35.0
SN74HCT273DWR	SOIC	DW	20	2000	367.0	367.0	45.0
SN74HCT273NSR	so	NS	20	2000	356.0	356.0	41.0
SN74HCT273NSR	so	NS	20	2000	367.0	367.0	45.0
SN74HCT273PWR	TSSOP	PW	20	2000	356.0	356.0	35.0

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 12-May-2023

### **TUBE**



### \*All dimensions are nominal

ı	Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
	SN74HCT273N	N	PDIP	20	20	506	13.97	11230	4.32





- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-150.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



### **MECHANICAL DATA**

# NS (R-PDSO-G\*\*)

# 14-PINS SHOWN

### PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



# N (R-PDIP-T\*\*)

# PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.





SOIC



- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



# PW (R-PDSO-G20)

# PLASTIC SMALL OUTLINE



- All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
  C. Publication IPC-7351 is recommended for alternate design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



### **IMPORTANT NOTICE AND DISCLAIMER**

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2023, Texas Instruments Incorporated